



# 11 HLEM 2020 – Asphere Metrology Detailed Programme

**preliminary**

<b>DAY 1</b>	<b>Tuesday, 17 March 2020</b>	<b>Evening</b>
<b>Start: 19:00</b>	<b>Get Together in Local Restaurant</b>	
	<b><u>Recommended Accomodation</u></b> <u>Best Western City Hotel, Hotel Deutsches Haus, Hotel Fürstenhof, Mercure Atrium Hotel, Vienna House Easy Braunschweig</u>	

<b>DAY 2</b>	<b>Wednesday, 18 March 2020</b> <i>Chair: Andreas Beutler; Mahr GmbH Göttingen; Germany</i>	<b>Morning</b>
<b>8:45</b>	<b>Arrival, Registration, Welcome Coffee</b>	
<b>9:30</b>	<b>Welcome to HLEM 2020 - Conference Opening, Overview and Outlook</b> <i>Frank Löffler; CC UPOB e.V.; Germany</i>	
<b>9:45</b>	<b>YSA 2020 – Young Scientist Award 2020 Introduction and Short Lectures of Nominated Young Scientists from Ultra-Precision Surface Engineering</b> <i>Moderation by Chair: Andreas Beutler; Mahr GmbH Göttingen; Germany and Nominated Speakers from Different Institutions</i>	
<b>10:15</b>	<b>Introduction to HLEM 2020 – Short Overview on Samples and Background of Measurements</b> <i>Jean-Michel Asfour; DIOPTIC GmbH; Germany</i>	



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<b>DAY 2</b>	<b>Wednesday, 18 March 2020</b> <b>Session - Centring of Optical Components</b> <i>Chair: Andreas Beutler; Mahr GmbH Göttingen; Germany</i>	<b>Morning</b>
10:30	<b>Centration Testing of Lenses - An Overview</b> <i>Felix Hahne; Trioptics GmbH; Germany</i>	
11:00	<b>Coffee Break, Technical Exhibition and YSA Poster Session</b>	
11:45	<b>CGH Based Precision Test of the Inner Centration of a Biconvex Asphere</b> <i>Frank Weidner; Dioptic GmbH; Germany</i>	
12:10	<b>Centration Measurements by Trioptics</b> <i>Felix Hahne; Trioptics GmbH; Germany</i>	
12:35	<b>A new Approach to Shape and Centration Measurement on Aspheres with New V-SPOT Technology</b> <i>Engelbert Hofbauer and Ronald Kometer; Hofbauer-Optik Mess- und Prüftechnik; Germany</i>	
13:00	<b>Lunch and Coffee Break, Technical Exhibition and YSA Poster Session</b>	



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DAY 2	Wednesday, 18 March 2020 Session - Additional Topics <i>Chair: Oltmann Riemer; Leibniz-Institut für Werkstofforientierte Technologien - IWT; Germany</i>	Afternoon
13:00	<b>Lunch and Coffee Break, Technical Exhibition and YSA Poster Session</b>	
14:00	<b>Optical Metrology Challenges in the Context of the ELT Programme</b> <i>Samuel Lévêque; ESO European Southern Observatory; Germany</i>	
14:25	<b>UP Manufacturing of Challenging Optical Functional Surfaces</b> <i>Kurt Haskic; LT Ultra-Precision Technology GmbH; Germany</i>	
14:50	<b>Referencing Topography Measurement Data of Optical Surfaces</b> <i>Andreas Müller; Metroshift; Germany</i>	
15:15	<b>Project 'Free-Form Measurement': Description of Standardized Measurement Procedures for Asphere Testing Using Pointwise Measurement Techniques</b> <i>Hanno Dierke; Technical University Braunschweig, Germany</i>	
15:35	<b>Coffee Break, Technical Exhibition and YSA Poster Session</b>	



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15:35	<b>Coffee Break, Technical Exhibition and YSA Poster Session</b>	
16:20	<b>Ion Beam Finishing of Optical Aluminium Surfaces</b> <i>Thomas Arnold; Leibniz Institut für IOM; Germany</i>	
16:45	<b>Characterization of Transmissive Segmented Freeform Optics using Experimental Ray Tracing</b> <i>Tobias Binkele; Hochschule Bremen, Germany</i>	
17:10	<b>Absolute Interferometry for Asphere Metrology</b> <i>Jan Kredba, TOPTEC; Czech Republic</i>	
17:30	<b>Summary and Closing of First Day</b> <i>Session Chair</i>	
19:00	<b>Conference Dinner in Local Restaurant</b>	
23:30	<b>Good Night!</b>	



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<b>DAY 3</b>	<b>Thursday, 19 March 2020</b> <b>Session - Additional Topics</b> <i>Chair: Jean-Michel Asfour; Dioptric GmbH; Germany</i>	<b>Morning</b>
9:00	<b>Welcome Coffee, Technical Exhibition and YSA Poster Session</b>	
9:30	<b>Opening of Second Day</b> <i>Session Chair</i>	
9:35	<b>Form Characterization using Low Coherence Reflection Shearing Interferometry</b> <i>Marcel Lotzgeselle, PTB; Germany</i>	
10:00	<b>Retrace Error Compensation in Absolute Interferometric Testing</b> <i>Marek Stašik, TOPTEC; Czech Republic</i>	
	<b>Session - Different Measuring Techniques</b> <i>Chair: Jean-Michel Asfour; Dioptric GmbH; Germany</i>	
10:25	<b>Comparison of Interferometric- and Point Sensor Measurement of Complex Optics</b> <i>Tobias Jörg Schröter; Mahr GmbH Standort Jena; Germany</i>	
10:50	<b>Coffee Break, Technical Exhibition and YSA Poster Session</b>	
11:35	<b>Non-Contact 3D Form Measurement of Complex Geometries by a Multi-Wavelength Interferometer</b> <i>Marc Wendel; Taylor Hobson; Germany</i>	



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12:00	<b>Round Robin Test by UA3P</b> <i>Tomofumi Morishita;</i> <i>Panasonic Production Engineering Co., Ltd; Japan</i>	
12:25	<b>NMF600 S Measurement Performance on UPOB Samples and Other Challenging Optics</b> <i>Rens Henselmans; Dutch United Instruments; The Netherlands</i>	
12:50	<b>Lunch and Coffee Break, Technical Exhibition and YSA Poster Session</b>	
13:50	<b>HLEM 2020 - Measurements at ITO</b> <i>Christof Pruss; ITO - University Stuttgart GmbH; Germany</i>	
14:15	<b>Intercomparison of Measurement Results</b> <i>Katherina Janzen; Physikalisch-Technische Bundesanstalt; Germany</i>	
14:45	<b>YSA 2020 – Young Scientist Award 2020 Ceremony</b> <i>Moderation by Jean-Michel Asfour; Dioptic GmbH; Germany</i>	
15:15	<b>Conference Closing and Outlook</b> <i>Session Chair</i>	
15:20	<b>End of Event and Departure</b>	